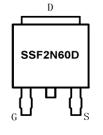
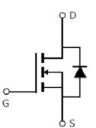


### **Main Product Characteristics**

V <sub>DSS</sub>	600V
R <sub>DS</sub> (on)	3.8Ω (typ.)
I <sub>D</sub>	2A







TO-252

Marking and Pin Assignment

Schematic Diagram

#### **Features and Benefits**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



### **Description**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

# **Absolute Max Rating**

Symbol	Parameter	Max.	Units	
I <sub>D</sub> @ TC = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V1	2		
I <sub>D</sub> @ TC = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V①	1.3	Α	
I <sub>DM</sub>	Pulsed Drain Current②	8		
D 070 0500	Power Dissipation③	42	W	
P <sub>D</sub> @TC = 25°C	Linear Derating Factor	0.34	W/°C	
V <sub>DS</sub>	Drain-Source Voltage	600	V	
V <sub>GS</sub>	V <sub>GS</sub> Gate-to-Source Voltage		V	
E <sub>AS</sub> Single Pulse Avalanche Energy @ L=53mH		116	mJ	
I <sub>AS</sub>	Avalanche Current @ L=53mH	2.1	А	
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C	





### **Thermal Resistance**

Symbol	Characteristics	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-case③	_	2.95	°CW
$R_{\theta JA}$	Junction-to-ambient (t $\leq$ 10s) $\stackrel{.}{ ext{4}}$	_	110	°C/W

## **Electrical Characteristics** $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	600	_	_	V	V <sub>GS</sub> = 0V, ID = 250μA	
D	Static Drain-to-Source on-resistance	_	3.8	4.5	Ω	V <sub>GS</sub> =10V,I <sub>D</sub> = 1.0A	
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance	_	8.2	_	12	T <sub>J</sub> = 125℃	
V	Gate threshold voltage	2	_	4	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$	
$V_{GS(th)}$	Gate threshold voltage	_	2.4	_	V	T <sub>J</sub> = 125℃	
I	Drain to Source leakage ourrent	_		1		$V_{DS} = 600V, V_{GS} = 0V$	
I <sub>DSS</sub>	Drain-to-Source leakage current	_		50	μA	T <sub>J</sub> = 125℃	
1	Cata ta Sauraa farusard laakaga	_	_	100	n 1	V <sub>GS</sub> =30V	
$I_{GSS}$	Gate-to-Source forward leakage	_	_	-100	nA	V <sub>GS</sub> = -30V	
Qg	Total gate charge	_	5.7	_		$I_D = 2.0A,$	
$Q_{gs}$	Gate-to-Source charge	_	1.7	_	nC	V <sub>DS</sub> =480V,	
$Q_{gd}$	Gate-to-Drain("Miller") charge	_	2.0	_		V <sub>GS</sub> = 10V	
t <sub>d(on)</sub>	Turn-on delay time	_	9.1	_			
t <sub>r</sub>	Rise time	_	6.3	_		$V_{GS}$ =10V, VDS=300V, $R_{GEN}$ =25 $\Omega$ , ID=2.0A	
t <sub>d(off)</sub>	Turn-Off delay time	_	23	_	ns		
tf	Fall time	_	13	_			
C <sub>iss</sub>	Input capacitance	_	329	_		V <sub>GS</sub> = 0V	
Coss	Output capacitance		32	_	pF	V <sub>DS</sub> = 25V	
C <sub>rss</sub>	Reverse transfer capacitance	_	4	_		f = 1MHz	

# **Source-Drain Ratings and Characteristics**

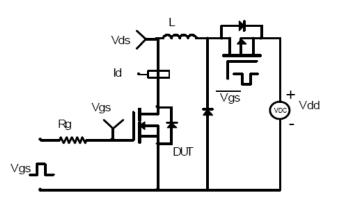
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current		_	2	А	MOSFET symbol
	(Body Diode)	_				showing the
I <sub>SM</sub>	Pulsed Source Current		_	8	А	integral reverse
	(Body Diode)	_				p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage	_	0.84	1.4	V	I <sub>S</sub> =1.9A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	_	357	_	ns	$T_J = 25^{\circ}\text{C}, I_F = 2\text{A},$
Qrr	Reverse Recovery Charge	_	1030	_	nC	di/dt = 100A/µs

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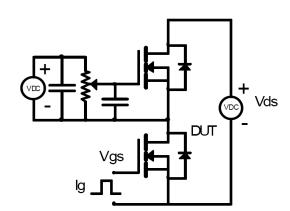


### **Test circuits and Waveforms**

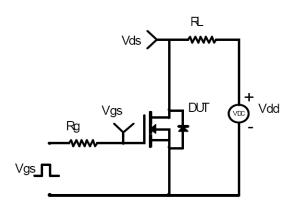
#### **EAS Test Circuit**



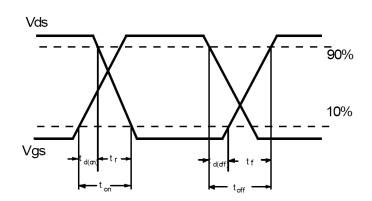
#### Gate charge test circuit



#### **Switching Time Test Circuit**



#### **Switching Waveforms**

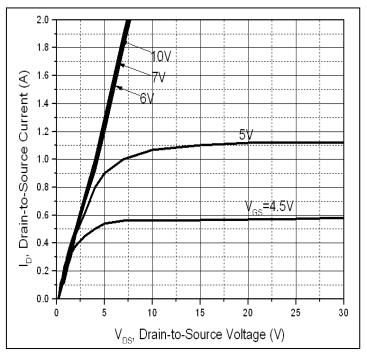


#### Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of  $R_{\texttt{9JA}}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



# Typical electrical and thermal characteristics



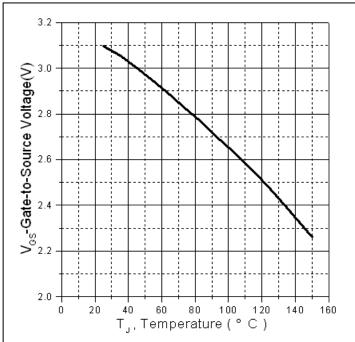


Figure 1: Typical Output Characteristics

Figure 2. Gate to source cut-off voltage

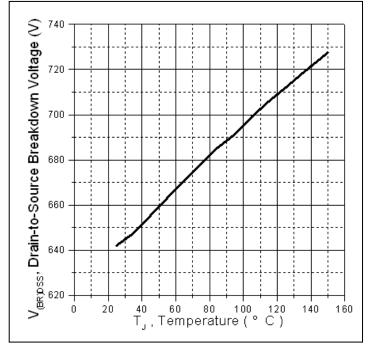


Figure 3. Drain-to-Source Breakdown Voltage Vs. **Case Temperature** 

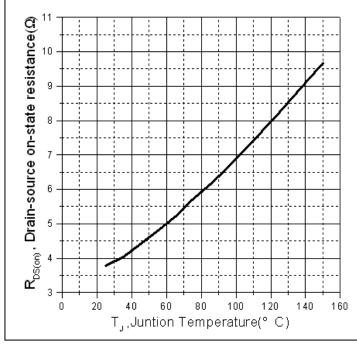


Figure 4: Normalized On-Resistance Vs. Case **Temperature** 



## Typical electrical and thermal characteristics

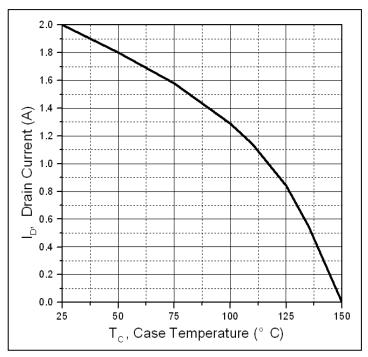


Figure 5. Maximum Drain Current Vs. Case Temperature

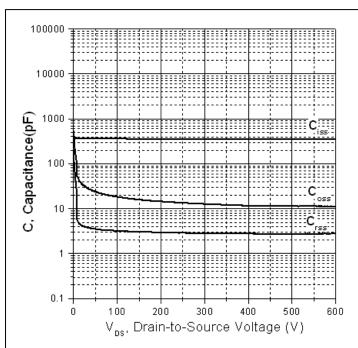


Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

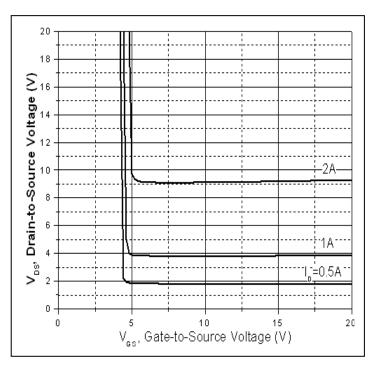


Figure 7. Drain-to-Source Voltage Vs. Gate-to-Source Voltage

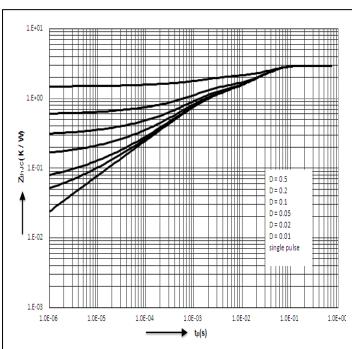
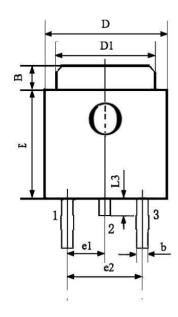


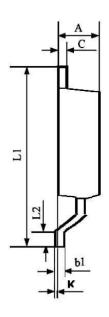
Figure8. Maximum Effective Transient Thermal Impedance, Junction-to-Case



# **Mechanical Data:**

### **TO-252 PACKAGE OUTLINE DIMENSION**





Symbol	Dimens	sion In Mill	imeters	Dimension In Inches		
Symbol	Min	Nom	Max	Min	Nom	Max
Α	2.200	-	2.400	0.087	-	0.094
В	0.950	-	1.250	0.037	-	0.049
b	0.500	-	0.700	0.020	-	0.028
b1	0.450	-	0.550	0.018	-	0.022
С	0.450	-	0.550	0.018	-	0.022
D	6.450	-	6.750	0.254	-	0.266
D1	5.200	-	5.400	0.205	-	0.213
Е	5.950	-	6.250	0.234	-	0.246
e1	2.240	-	2.340	0.088	-	0.092
e2	4.430	-	4.730	0.174	-	0.186
L1	9.450	-	9.950	0.372	-	0.392
L2	1.250	-	1.750	0.049	-	0.069
L3	0.600	-	0.900	0.024	-	0.035
K	0.000	-	0.100	0.000	-	0.004

Version: 1.0





## **Ordering and Marking Information**

Device Marking: SSF2N60D

Package (Available)
TO-252(D-PAK)
Operating Temperature Range
C: -55 to 150 °C

## **Devices per Unit (options)**

Package	Units/Tape	Tapes/Inner	<b>Units/Inner</b>	Inner	Units/Carton
Type		Box	Box	Boxes/Carton	Box
				Box	
TO-252	2500	2	5000	7	35000
TO-252	2500	1	2500	10	25000
TO-252	800	5	4000	8	32000

## **Reliability Test Program**

Test Item	Conditions	Duration	Sample Size
High	T <sub>j</sub> =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V <sub>DSS</sub> /V <sub>CES</sub> /VR	1000 hours	
Bias(HTRB)			
High	T <sub>j</sub> =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V <sub>GSS</sub>	500 hours	
Gate		1000 hours	
Bias(HTGB)			

Version: 1.0





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